

# Device Modeling Report

COMPONENTS: PHOTOCOUPLER  
PART NUMBER: PC829  
MANUFACTURER: SHARP



**Bee Technologies Inc.**

## DIODE MODEL

Pspice model Parameter	Model description
IS	Saturation Current
N	Emission Coefficient
RS	Series Resistance
IKF	High-injection Knee Current
CJO	Zero-bias Junction Capacitance
M	Junction Grading Coefficient
VJ	Junction Potential
ISR	Recombination Current Saturation Value
BV	Reverse Breakdown Voltage(a positive value)
IBV	Reverse Breakdown Current(a positive value)
TT	Transit Time

## BIPOLAR JUNCTION TRANSISTOR MODEL

Pspice model parameter	Model description
NR	Reverse Emission Coefficient
RB	Base Resistance
RC	Series Collector Resistance
CJE	Zero-bias Emitter-Base Junction Capacitance
CJC	Zero-bias Collector-Base Junction Capacitance
TF	Forward Transit Time
TR	Reverse Transit Time

## VOLTAGE CONTROLLED VOLTAGE SOURCE MODEL(VCVS)

E<Name><(+)Node><(−)Node>VALUE={Expression}

E<Name><(+)Node><(−)Node>TABLE={Expression}

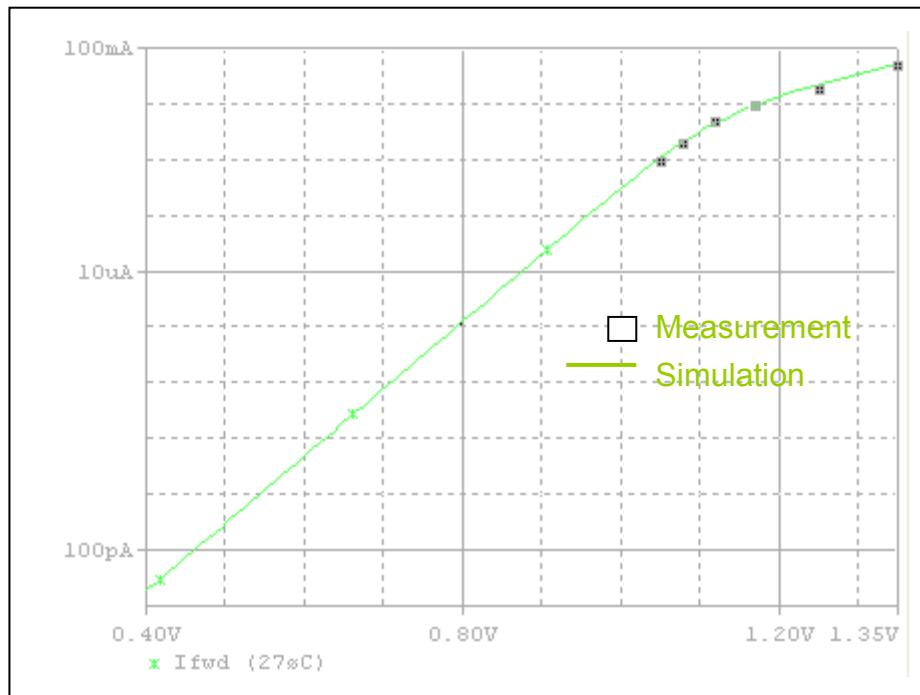
## **VOLTAGE CONTROLLED CURRENT SOURCE MODEL(VCCS)**

E<Name><(+)Node><(−)Node>VALUE={Expression}

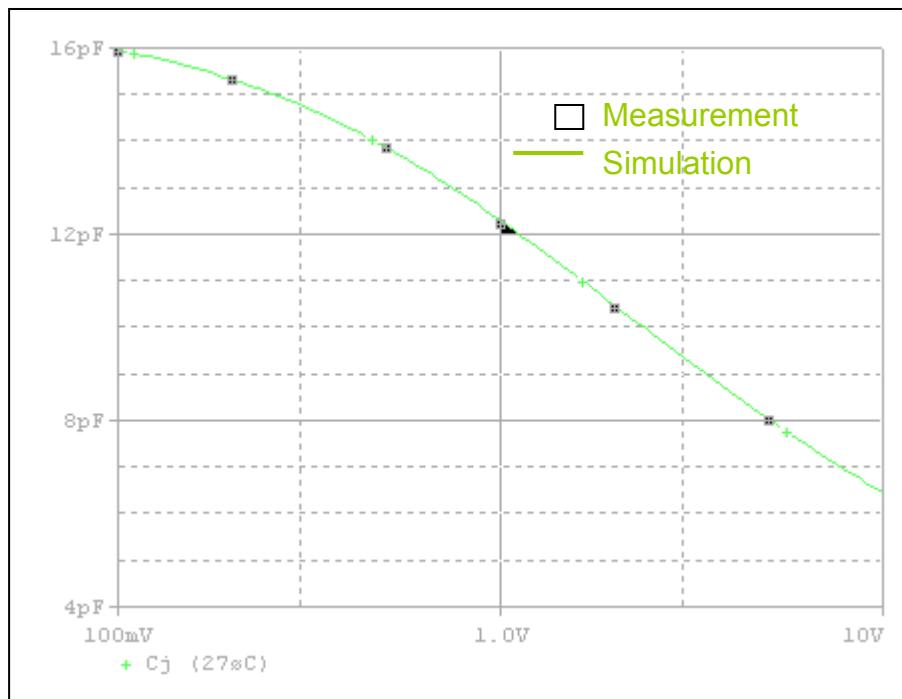
### **CURRENT CONTROLLED MODEL(W)**

Pspice model parameter	Model description
IOFF	Controlling current to Off state
ION	Controlling current to On state
ROFF	Off Resistance
RON	On Resistance

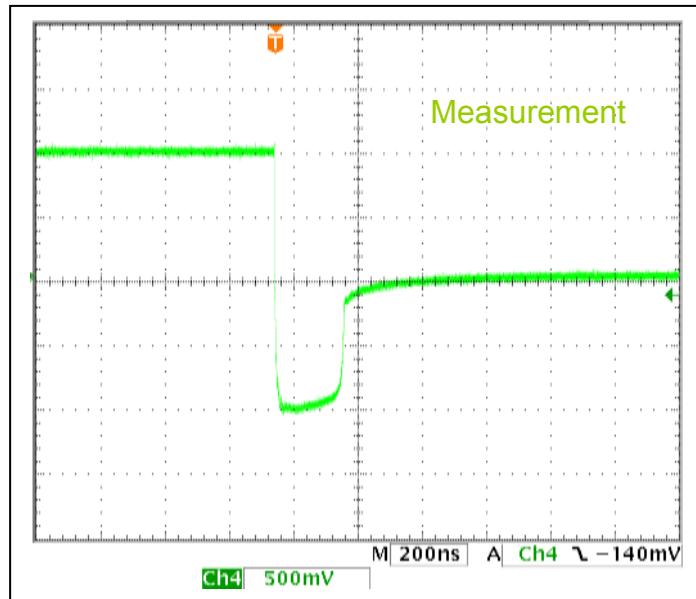
## Input Device Forward Current Characteristics



## Input Device Junction Capacitance Characteristics



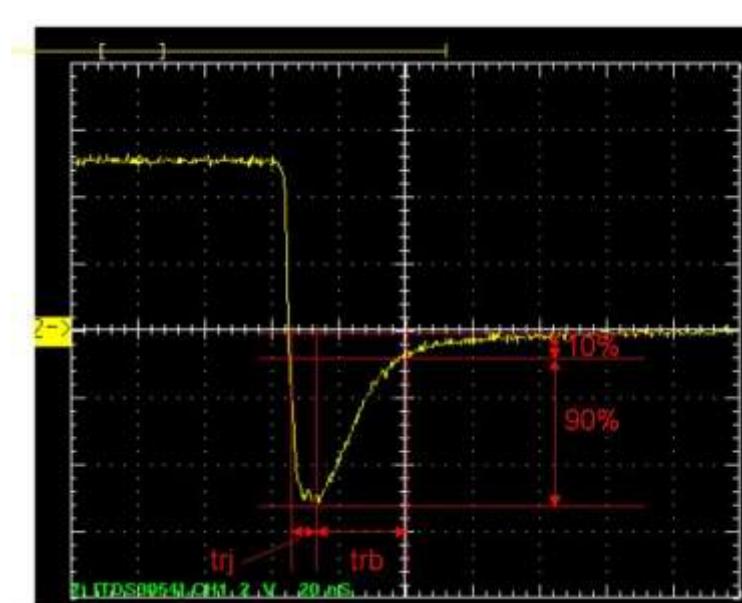
## Input Device Reverse Recovery Characteristics



$trj=196n(s)$

$trb=60n(s)$

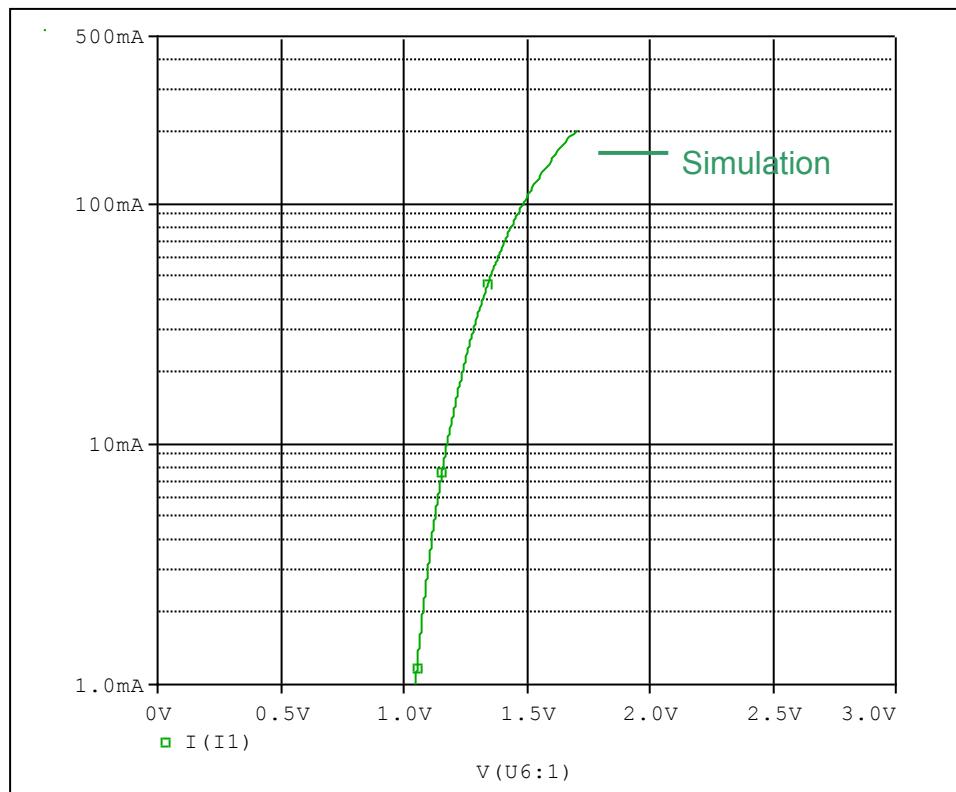
Conditions: Ifwd=Irev=0.04(A), RI=50



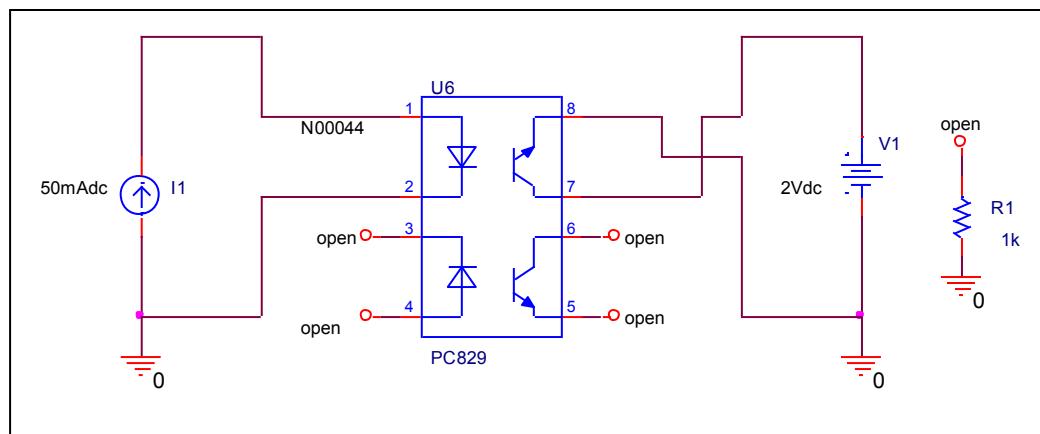
Relation between  $trj$  and  $trb$

## LED IV Curve Characteristics

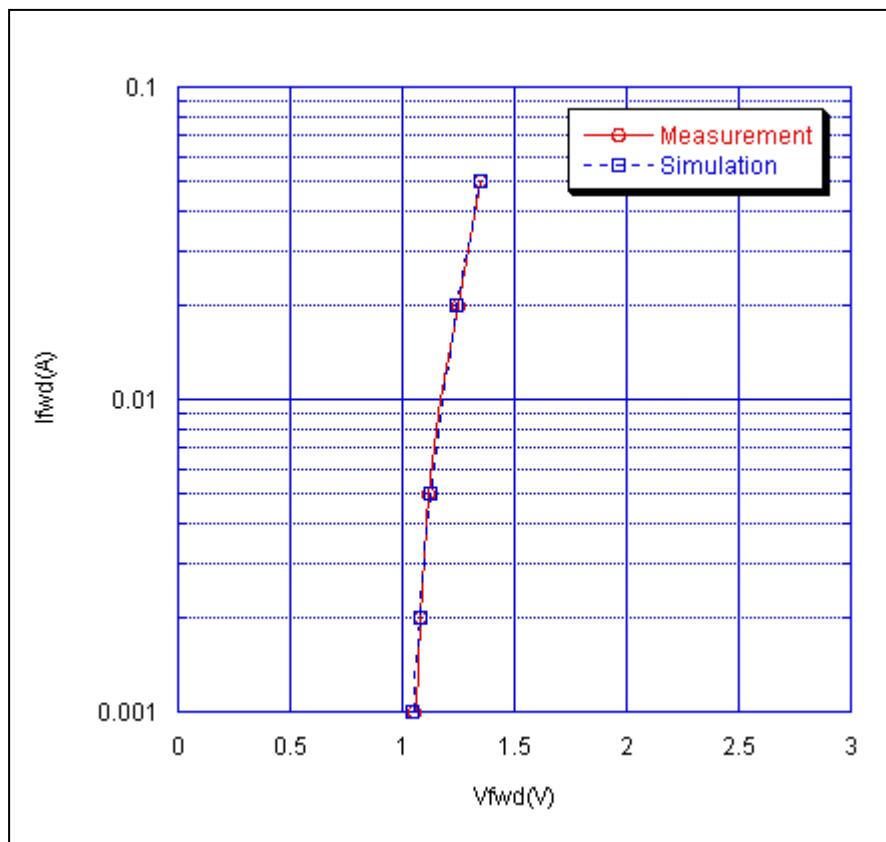
Simulation result



Evaluation Circuit



Comparison Graph

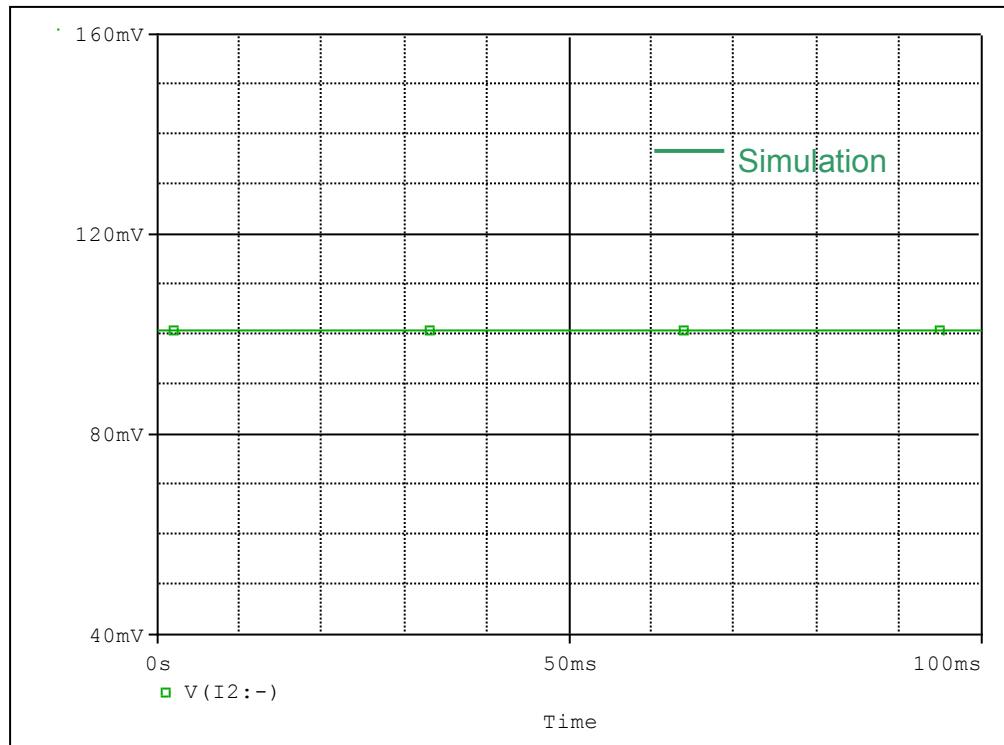


Comparison Table

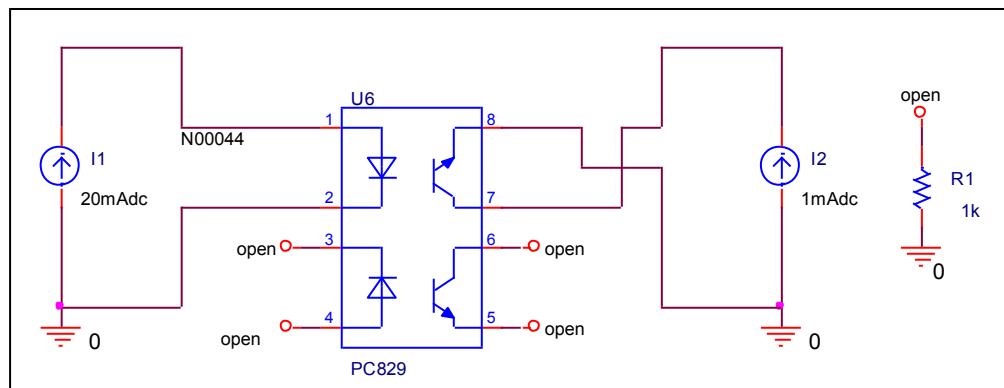
$I_{fwd}(A)$	$V_{fwd}(V)$		% Error
	Measurement	Simulation	
0.001	1.050	1.047	-0.286
0.002	1.080	1.078	-0.185
0.005	1.120	1.126	0.536
0.01	1.170	1.176	0.513
0.02	1.250	1.238	-0.960
0.05	1.350	1.352	0.148

## Transistor Saturation Characteristics

### Simulation result



### Evaluation Circuit



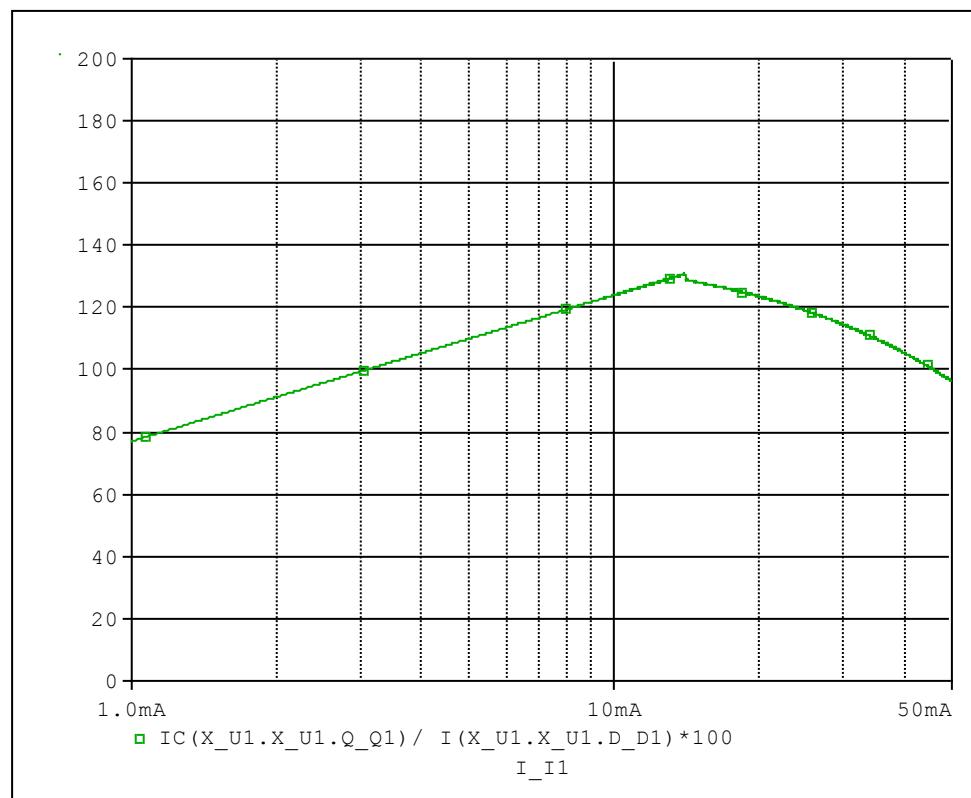
### Comparison Table

	Measurement	Simulation	% Error
$V_{ce(sat)} (V)$	0.100	0.100	0.000

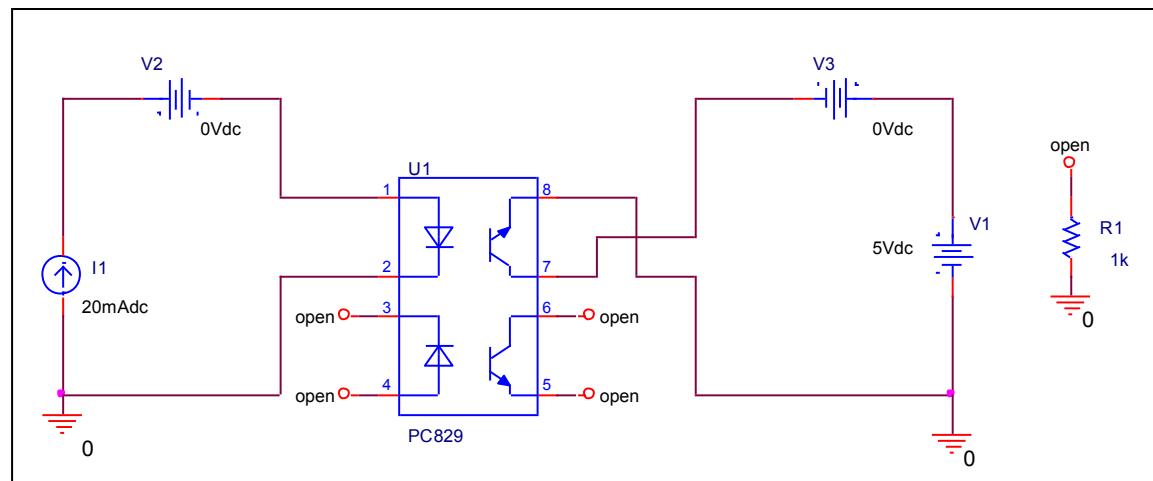
## CTR(Current Transfer Ratio) Characteristics

Simulation result

Simulation



Evaluation Circuit



## Rise Curve Table

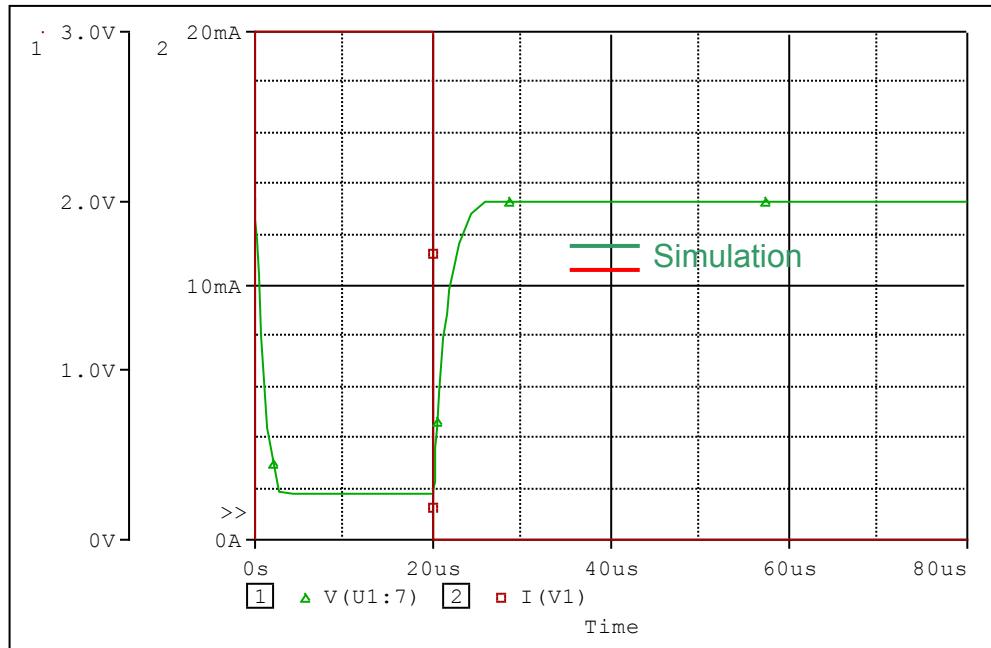
If(mA)	CTR(%)		% Error
	Measurement	Simulation	
1.000	77.000	76.993	-0.009
2.000	94.000	91.228	-2.949
5.000	115.000	110.149	-4.218
10.000	128.000	124.382	-2.827
14.000	130.000	130.955	0.735

## Fall Curve Table

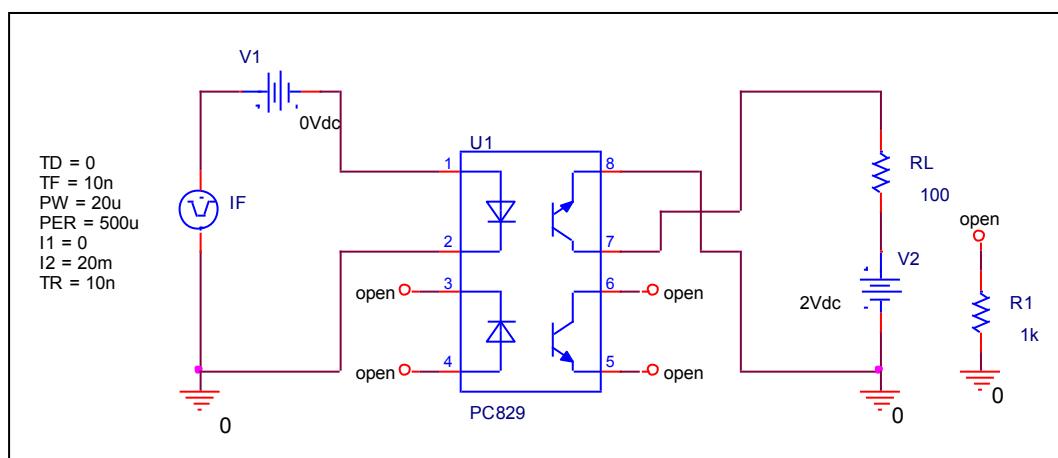
If(mA)	CTR(%)		% Error
	Measurement	Simulation	
14.000	130.000	130.955	0.735
20.000	128.000	123.214	-3.739
30.000	120.000	114.436	-4.637
40.000	107.000	104.994	-1.875
47.000	101.000	98.619	-2.357

## Switching Time Characteristics

### Simulation result



### Evaluation Circuit



### Comparison Table

Vce=2V,RL=100Ω	Measurement	Simulation	% Error
ts (us)	0.210	0.209	-0.476
tf (us)	3.200	3.195	-0.156